

Notice of References Cited	Application/Control No. 10/630,643	Applicant(s)/Patent Under Reexamination YEW ET AL.	
	Examiner Leonardo Andújar	Art Unit 2826	Page 1 of 1

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	C	US-6,225,207 B1	05-2001	Parikh, Suketu A.	438/622
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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